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With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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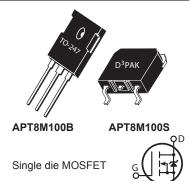


APT8M100B APT8M100S

1000V, 8A, 1.80Ω Max

N-Channel MOSFET

Power MOS 8^{TM} is a high speed, high voltage N-channel switch-mode power MOSFET. A proprietary planar stripe design yields excellent reliability and manufacturability. Low switching loss is achieved with low input capacitance and ultra low C_{rss} "Miller" capacitance. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control slew rates during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency. Reliability in flyback, boost, forward, and other circuits is enhanced by the high avalanche energy capability.



FEATURES

- · Fast switching with low EMI/RFI
- Low R_{DS(on)}
- Ultra low C_{rss} for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

TYPICAL APPLICATIONS

- · PFC and other boost converter
- · Buck converter
- · Two switch forward (asymmetrical bridge)
- · Single switch forward
- Flyback
- Inverters

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
L	Continuous Drain Current @ T _C = 25°C	8	
'D	Continuous Drain Current @ T _C = 100°C	5	А
I _{DM}	Pulsed Drain Current ^①	27	
V _{GS}	Gate-Source Voltage	±30	V
E _{AS}	Single Pulse Avalanche Energy ©	415	mJ
I _{AR}	Avalanche Current, Repetitive or Non-Repetitive	4	Α

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit	
P _D	Total Power Dissipation @ T _C = 25°C			290	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.43	°C/W	
R _{ecs}	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15			
T_J , T_{STG}	Operating and Storage Junction Temperature Range	-55		150	°C	
T _L	Soldering Temperature for 10 Seconds (1.6mm from case)			300		
W _T	Package Weight		0.22		OZ	
			6.2		g	
Torque	Mounting Touris (TO 247 Poolsons) C 22 or M2 consu			10	in·lbf	
	Mounting Torque (TO-247 Package), 6-32 or M3 screw			1.1	N·m	

Static Characteristics

T_J = 25°C unless otherwise specified

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{BR(DSS)}	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250 \mu A$	1000			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I _D = 250µA		1.15		V/°C
R _{DS(on)}	Drain-Source On Resistance [®]	$V_{GS} = 10V, I_D = 4A$		1.53	1.80	Ω
V _{GS(th)}	Gate-Source Threshold Voltage	\/ -\/ -0.5m/	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}$, $I_{D} = 0.5 \text{mA}$		-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 1000V$ $T_{J} = 25^{\circ}C$			100	
DSS	Zero Gate voltage Drain Current	$V_{GS} = 0V$ $T_J = 125^{\circ}C$			500	μΑ
I _{GSS}	Gate-Source Leakage Current	V _{GS} = ±30V			±100	nA

Dvnamic Characteristics

T₁ = 25°C unless otherwise specified

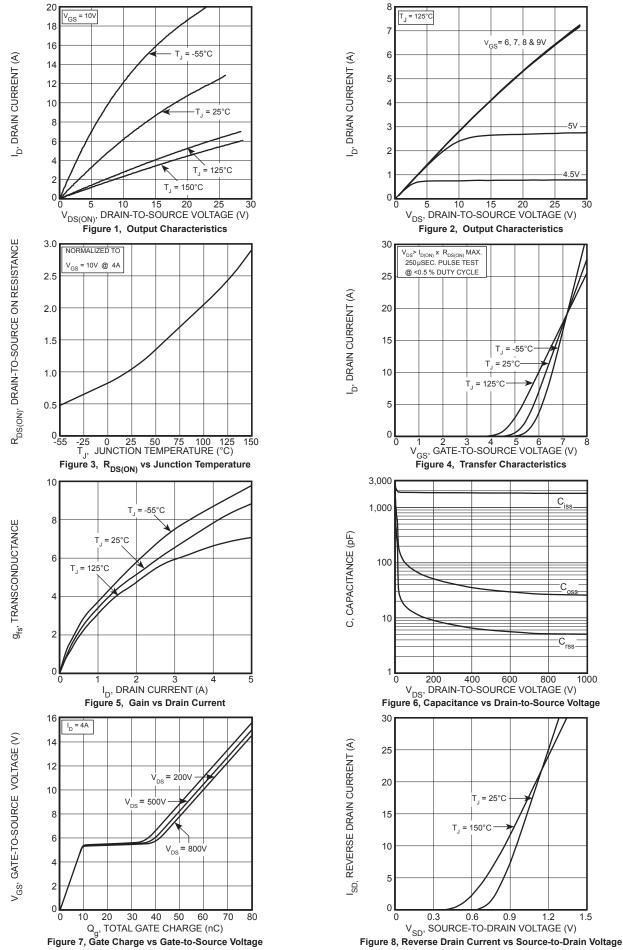
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
g _{fs}	Forward Transconductance	V _{DS} = 50V, I _D = 4A		7.5		S
C _{iss}	Input Capacitance	V 0V V 0FV		1885		
C _{rss}	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		25		
C _{oss}	Output Capacitance	1 111112		160		
$C_{o(cr)} \textcircled{4}$	Effective Output Capacitance, Charge Related	V 9V V 9VV 90VV		65		pF
C _{o(er)} ⑤	Effective Output Capacitance, Energy Related	V _{GS} = 0V, V _{DS} = 0V to 667V		33		
Q _g	Total Gate Charge	V 04:40V 1 4A		60		
Q_{gs}	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 4A,$		10		nC
Q_{gd}	Gate-Drain Charge	V _{DS} = 500V		27		
t _{d(on)}	Turn-On Delay Time	Resistive Switching		8.5		
t _r	Current Rise Time	V _{DD} = 667V, I _D = 4A		7.8		ns
t _{d(off)}	Turn-Off Delay Time	$R_{G} = 10\Omega^{\textcircled{6}}, V_{GG} = 15V$		29		115
t _f	Current Fall Time			7.2		

Source-Drain Diode Characteristics

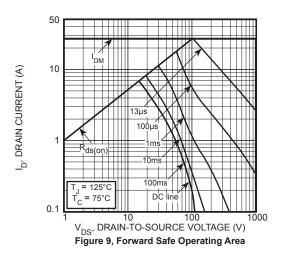
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
I _s	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n			8	A
I _{SM}	Pulsed Source Current (Body Diode) ^①	integral reverse p-n junction diode (body diode)			27	
V _{SD}	Diode Forward Voltage	$I_{SD} = 4A, T_{J} = 25^{\circ}C, V_{GS} = 0V$			1.0	V
t _{rr}	Reverse Recovery Time	I _{SD} = 4A, V _{DD} = 100V ^③		1030		ns
Q _{rr}	Reverse Recovery Charge	$di_{SD}/dt = 100A/\mu s$, $T_J = 25^{\circ}C$		18		μC
dv/dt	Peak Recovery dv/dt	$I_{SD} \le 4A$, di/dt $\le 1000A/\mu s$, $V_{DD} = 667V$, $T_{J} = 125^{\circ}C$			10	V/ns

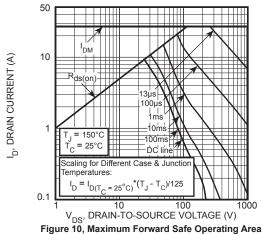
- (1) Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at $T_J = 25$ °C, L = 51.88mH, $R_G = 25\Omega$, $I_{AS} = 4A$.
- \bigcirc Pulse test: Pulse Width < 380µs, duty cycle < 2%.
- $\begin{array}{l} \textcircled{4} \quad \text{$C_{o(cr)}$ is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of $V_{(BR)DSS}$.} \\ \textcircled{5} \quad \text{$C_{o(er)}$ is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of $V_{(BR)DSS}$.} \\ \textbf{V_{DS} less than $V_{(BR)DSS}$, use this equation: $C_{o(er)}$ = -5.47E-8/V_{DS}^2 + 9.66E-9/V_{DS} + 1.87E-11.} \end{array}$
- (MIC4452)

Microsemi reserves the right to change, without notice, the specifications and information contained herein.



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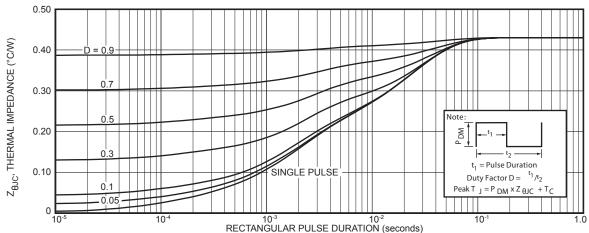
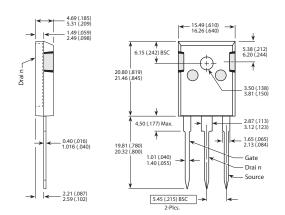


Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

TO-247 (B) Package Outline

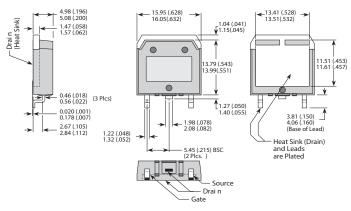
@1 SAC: Tin, Silver, Copper



Dimensions in Millimeters (Inches)

D³PAK Package Outline

@3 100% Sn Plated



Dimensions in Millimeters (Inches)